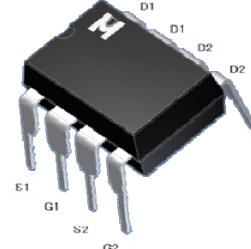
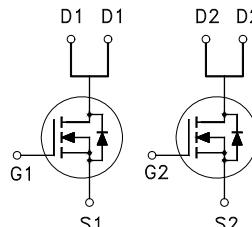


Dual N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV _{DSS}	60V
R _{DSON} (MAX.)	40mΩ
I _D	6A



UIS, 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V _{GS}	±20	V
Continuous Drain Current	T _C = 25 °C	I _D	6	A
	T _C = 100 °C		4.3	
Pulsed Drain Current ¹		I _{DM}	24	
Avalanche Current		I _{AS}	12	
Avalanche Energy	L = 0.1mH, ID=12A, RG=25Ω	E _{AS}	7.2	mJ
Repetitive Avalanche Energy ²	L = 0.05mH	E _{AR}	3.6	
Power Dissipation	T _C = 25 °C	P _D	5	W
	T _C = 100 °C		2	
Operating Junction & Storage Temperature Range		T _j , T _{stg}	-55 to 150	°C

100% UIS testing in condition of V_D=30V, L=0.1mH, V_G=10V, I_L=7.5A, Rated V_{DS}=60V N-CH

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	R _{θJC}	25	62.5	°C / W
Junction-to-Ambient ³	R _{θJA}			

¹Pulse width limited by maximum junction temperature.

²Duty cycle ≤ 1%

³62.5°C / W when mounted on a 1 in² pad of 2 oz copper.

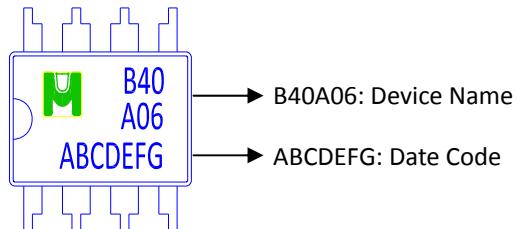
ELECTRICAL CHARACTERISTICS ($T_c = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.0	2.0	3.2	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 48V, V_{GS} = 0V$			1	μA
		$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			25	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 5V, V_{GS} = 10V$	6			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 10V, I_D = 6A$		34	40	$\text{m}\Omega$
		$V_{GS} = 5V, I_D = 5A$		47	60	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 6A$		16		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 30V, f = 1\text{MHz}$		1112		pF
Output Capacitance	C_{oss}			86		
Reverse Transfer Capacitance	C_{rss}			72		
Total Gate Charge ^{1,2}	Q_g	$V_{DS} = 30V, V_{GS} = 10V, I_D = 6A$		29		nC
Gate-Source Charge ^{1,2}	Q_{gs}			3.3		
Gate-Drain Charge ^{1,2}	Q_{gd}			7.4		
Turn-On Delay Time ^{1,2}	$t_{d(\text{on})}$	$V_{DS} = 30V, I_D = 1A, V_{GS} = 10V, R_{GS} = 6\Omega$		7		nS
Rise Time ^{1,2}	t_r			22		
Turn-Off Delay Time ^{1,2}	$t_{d(\text{off})}$			17		
Fall Time ^{1,2}	t_f			25		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ\text{C}$)						
Continuous Current	I_S				2.3	A
Pulsed Current ³	I_{SM}				9.2	
Forward Voltage ¹	V_{SD}	$I_F = I_S, V_{GS} = 0V$			1.2	V

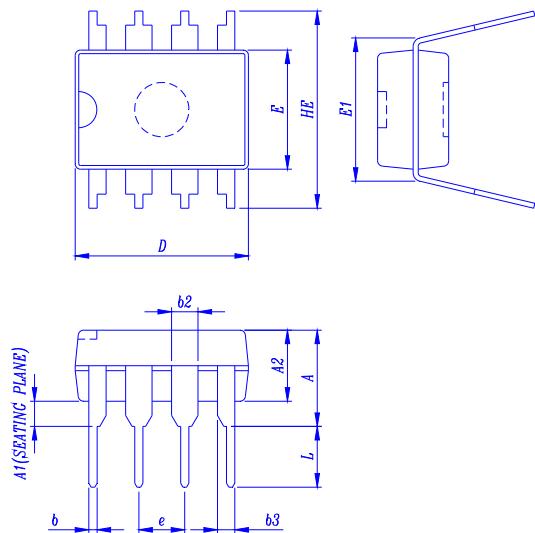
¹Pulse test : Pulse Width $\leq 300 \mu\text{sec}$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.³Pulse width limited by maximum junction temperature.

Ordering & Marking Information:

Device Name: EMB40A06S for DIP-8



Outline Drawing



Dimension in mm

Dimension	A	A1	A2	b	b2	b3	c	D	E	E1	e	HE	L
Min.		0.38	2.92	0.25	1.14	0.76	0.20	9.01	6.09	7.62			2.92
Typ.											2.54		
Max.	5.34		4.96	0.56	1.78	1.15	0.36	10.16	7.12	8.26		10.92	3.81

